MBX2 Hipot in Helium

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 10/21/2004

Test Time: 03:32:42 AM

User Name: ECB 10/20/04

Device Tested

Model Number: LBX M and N IN HELIUM

Serial Number: Box G MBX2

Setup Filename:

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand M-1,2,3,5,6,7	28	1	Pass	Pass	60.0s	1.40KV	0.3microamps
2	DC Withstand N-4,5,6,7	28	2	Pass	Pass	60.0s	1.40KV	0.3microamps
3	DC Withstand M-4, N-1,2,3	28	3	Pass	Pass	60.0s	0.65KV	0.2microamps
~~4~~	~~AC Withstand~~	~~28~~	~~4~~	~~Fail~~	~~Hi-Limit~~	~~0.2s~~	0.00KV	~~0.011mA~~
~~5~~	~~AC Withstand~~	~~28~~	~~5~~	~~Fail~~	~~Hi-Limit~~	~~0.2s~~	~~0.00KV~~	~~0.011mA~~
~~6~~	~~AC Withstand~~	~~28~~	~~6~~	~~Pass~~	~~Pass~~	~~1.0s~~	~~1.20KV~~	~~0.000mA~~

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 10/22/2004

Test Time: 12:53:15 AM

User Name: EGB 10/21/04

Device Tested

Model Number: LBX RTD 1-12 IN HELIUM

Serial Number: Box G MBX2

Setup Filename:

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	32	1	Pass	Pass	60.0s	0.20KV	0.0microamps
~~2~~	~~AC Withstand~~	~~32~~	~~2~~	~~Fail~~	~~Abort~~	~~0.4s~~	~~1.20KV~~	~~0.000mA~~

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 10/22/2004

Test Time: 12:57:25 AM

User Name: EEB 10/21/04

Device Tested

Model Number: LBX RTD 13-19 IN HELIUM

Serial Number: Box G MBX2

Setup Filename:

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	32	1	Pass	Pass	60.0s	0.20KV	0.0microamps
~~2~~	~~AC Withstand~~	~~32~~	~~2~~	~~Fail~~	~~Abort~~	~~0.5s~~	~~1.20KV~~	~~0.000mA~~